



CT3400-R3

N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} 30 V
- Drain-Source On-Resistance
 - $R_{DS(ON)}$ 23.5mΩ, at $V_{GS} = 10V$, $I_{DS} = 6.0A$
 - $R_{DS(ON)}$ 26.5mΩ, at $V_{GS} = 4.5V$, $I_{DS} = 5.0A$
- Continuous Drain Current at $T_A=25^\circ C$ $I_D = 5.8A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

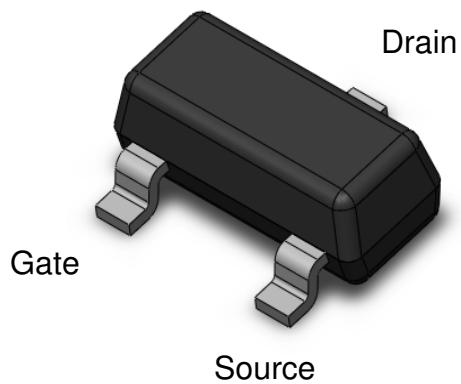
Description

The CT3400-R3 uses high performance Trench Technology to provide excellent $R_{DS(ON)}$ and low gate charge which is suitable for most of the synchronous buck converter applications .

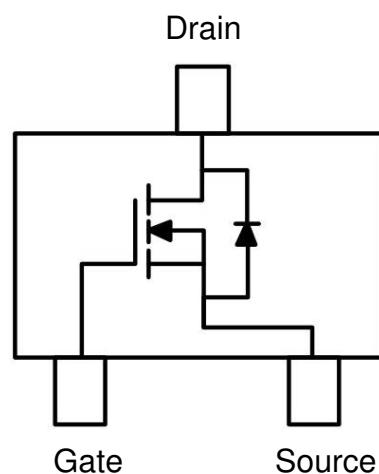
Applications

- Power Management
- LED Display
- DC-DC System
- LCD Panel

Package Outline



Schematic





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Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
V_{DS}	Drain-Source Voltage	30	V	
V_{GS}	Gate-Source Voltage	± 12	V	
I_D	Continuous Drain Current @ $T_A=25^\circ\text{C}$	5.8	A	1
I_{DM}	Pulsed Drain Current	15	A	1
P_D	Total Power Dissipation @ $T_A=25^\circ\text{C}$	1.4	W	2
T_{STG}	Storage Temperature Range	-55 to 150	°C	
T_J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\Theta JA}$	Thermal Resistance Junction-Ambient ($t=10\text{s}$)		-	175	-	°C /W	1,4



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Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B _{VDSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = 250μA	30	-	-	V	
I _{DSS}	Drain-Source Leakage Current	V _{DS} = 30V, V _{GS} = 0V	-	-	1	μA	
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±12V, V _{DS} = 0V	-	-	±100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R _{DS(ON)}	Drain-Source On-Resistance	V _{GS} = 10V, I _D = 6.0A	-	23.5	28	mΩ	3
		V _{GS} = 4.5V, I _D = 5.0A	-	26.5	38	mΩ	
V _{GS(TH)}	Gate-Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250μA	0.7	-	1.4	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C _{ISS}	Input Capacitance	V _{DS} = 10V , V _{GS} = 0V, f=1MHz	-	600	-	pF	
C _{OSS}	Output Capacitance		-	61	-		
C _{RSS}	Reverse Transfer Capacitance		-	50	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
T _{D(ON)}	Turn-On Delay Time	V _{DS} = 10V , V _{GS} = 4.5V, R _G = 6Ω, I _D = 5.8A	-	2	-	ns	
T _R	Rise Time		-	31.2	-		
T _{D(OFF)}	Turn-Off Delay Time		-	16.7	-		
T _F	Fall Time		-	6.7	-		
Q _G	Total Gate Charge	V _{DS} = 10V , V _{GS} = 4.5V, I _D = 5.8A	-	70	-	nC	
Q _{GS}	Gate-Source Charge		-	1.5	-		
Q _{GD}	Gate-Drain (Miller) Charge		-	2	-		



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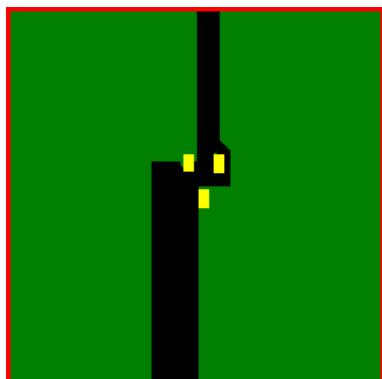
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Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_D = 1.0A$			1.2	V	
I_{SD}	Body Diode Continuous Current				1.0	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



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Typical Characteristic Curves

Drain Current vs Drain-Source Voltage

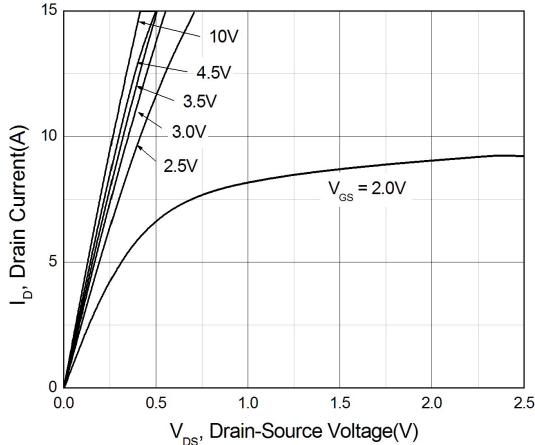


Figure 1

Gate Source Voltage vs Drain Current

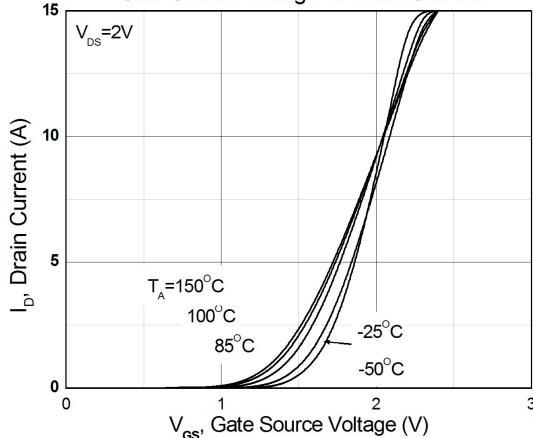


Figure 2

Drain Current vs On Resistance

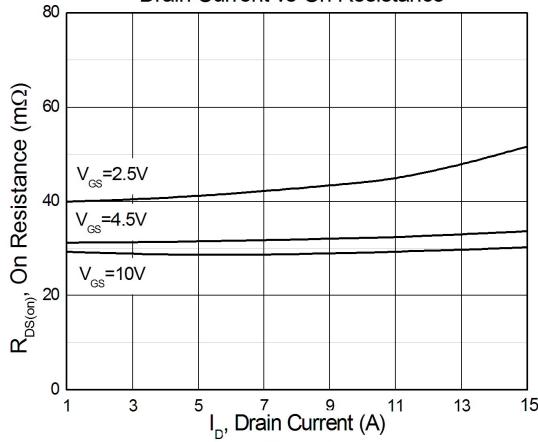


Figure 3

Drain Current vs On Resistance

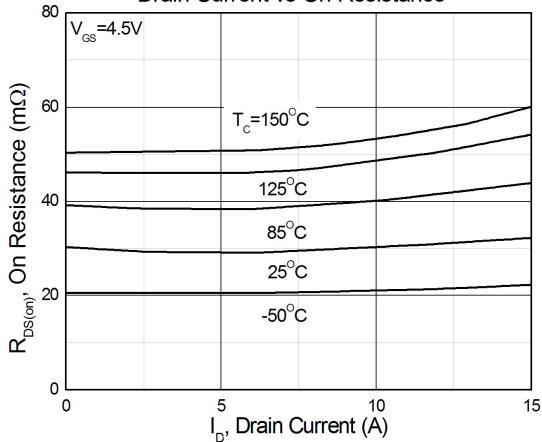


Figure 4

Junction Temperature vs On Resistance

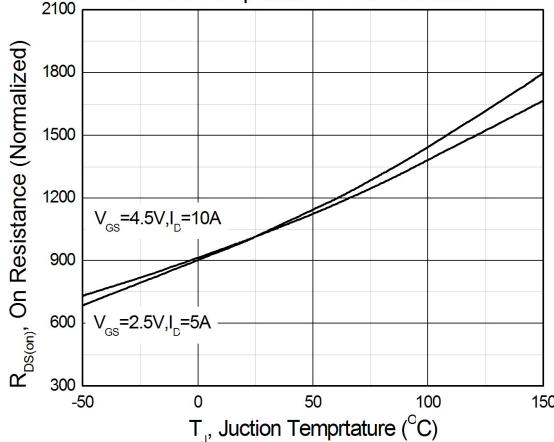


Figure 5

Junction Temperature vs On Resistance

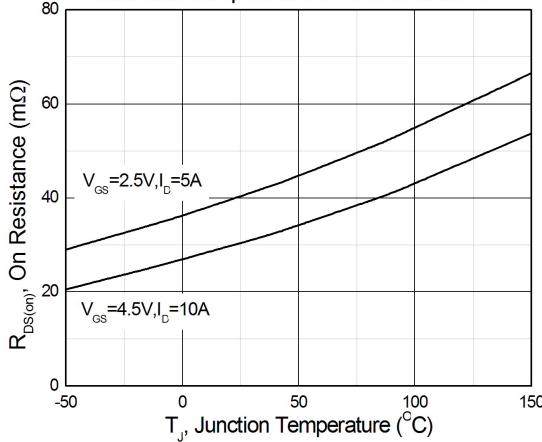
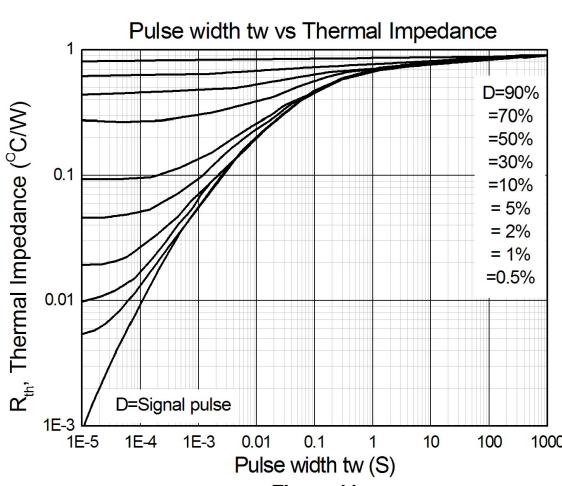
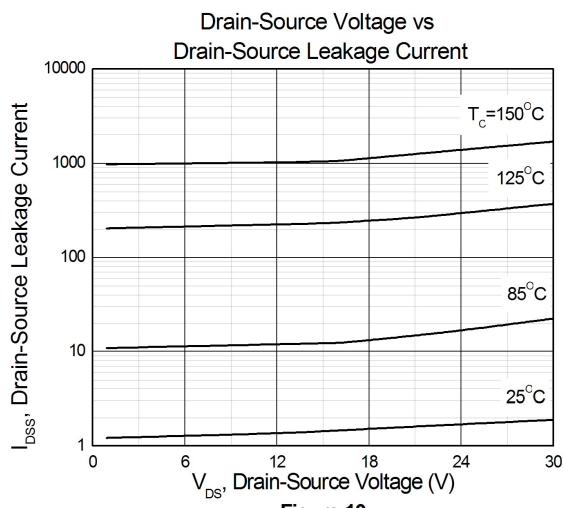
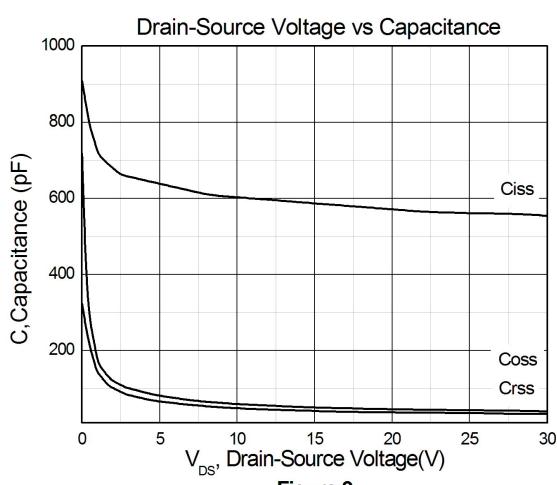
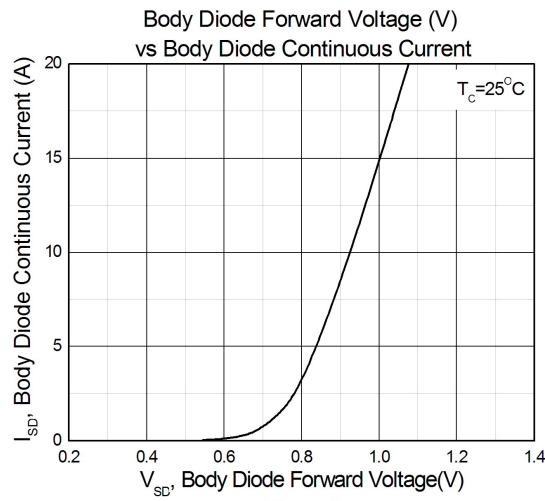
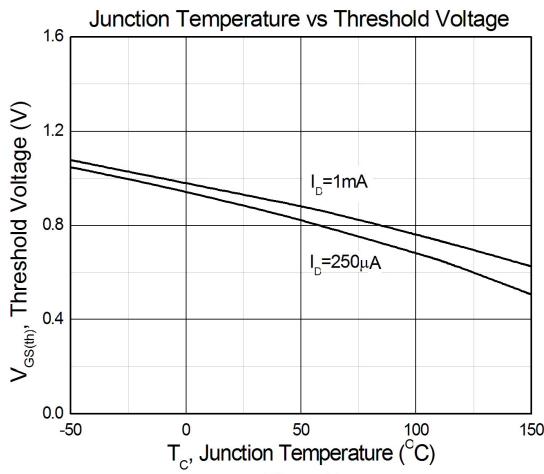


Figure 6



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Test Circuits & Waveforms

Figure 12: Gate Charge Test Circuit

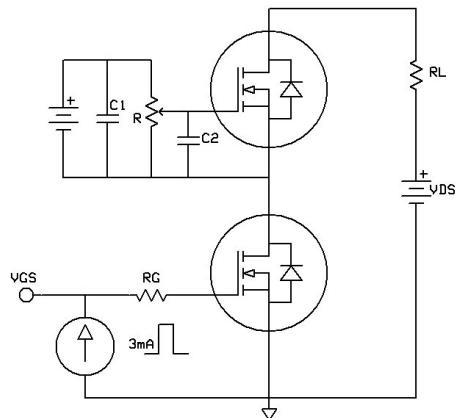


Figure 13: Gate Charge Waveform

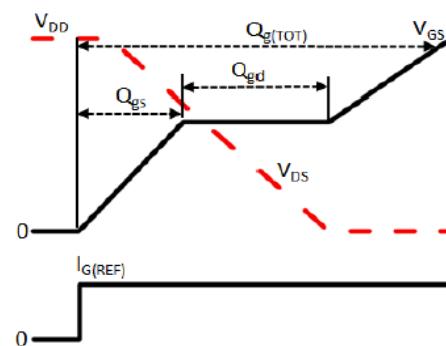


Figure 14: Switching Time Test Circuit

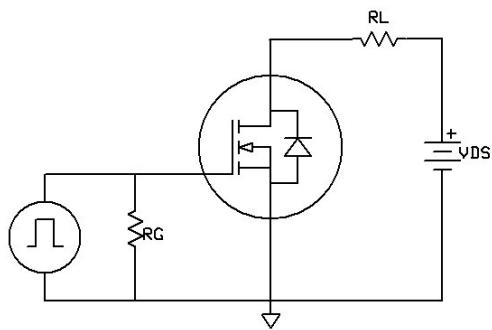
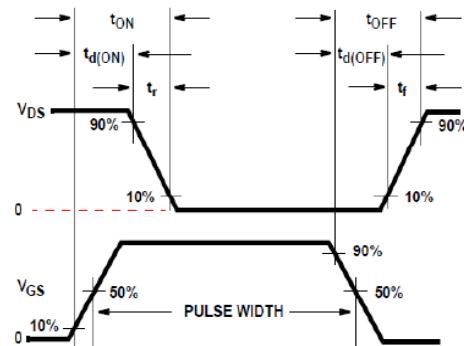


Figure 15: Switching Time Waveform

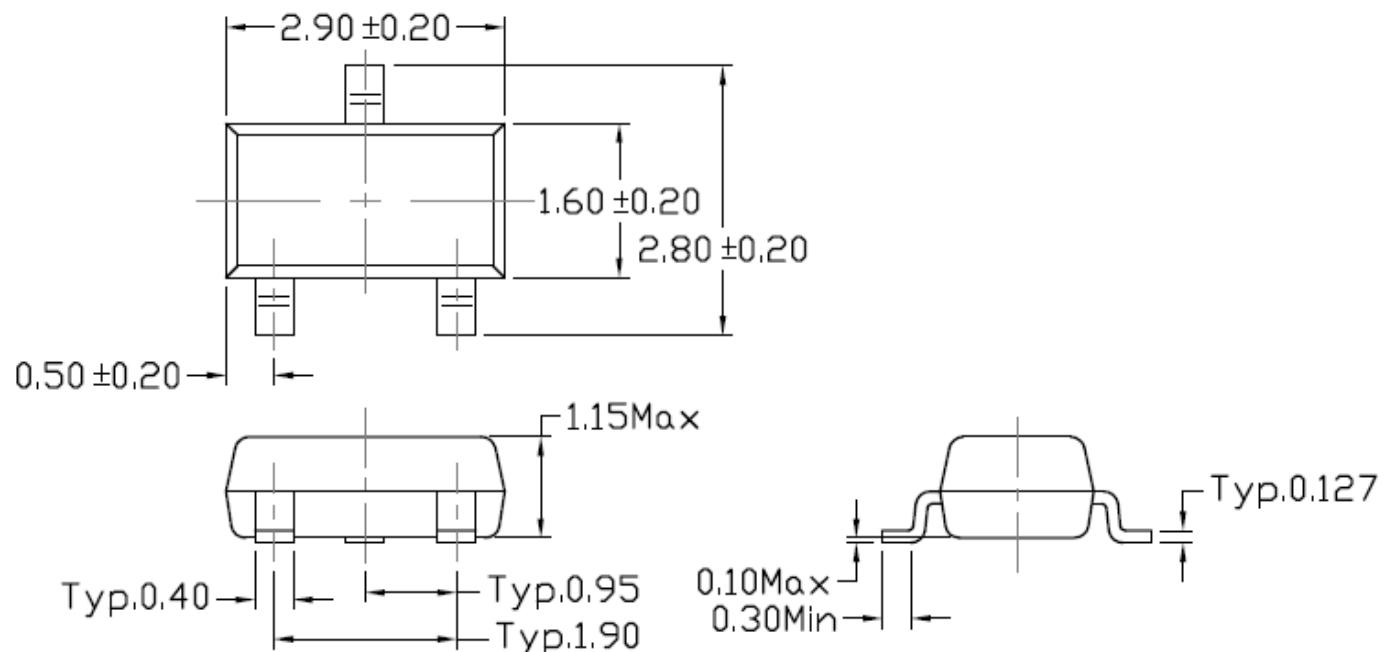




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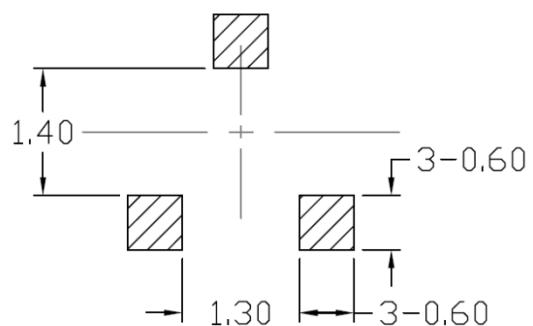
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Package Dimension (SC-59)



Note: Dimensions in mm

Recommended pad layout for surface mount leadform



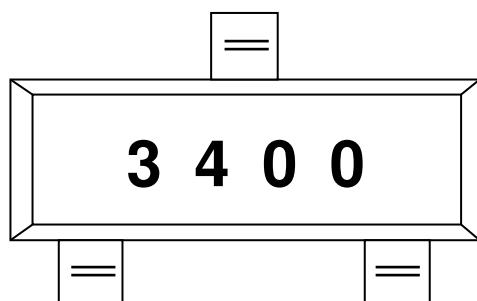
Note: Dimensions in mm



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Marking Information



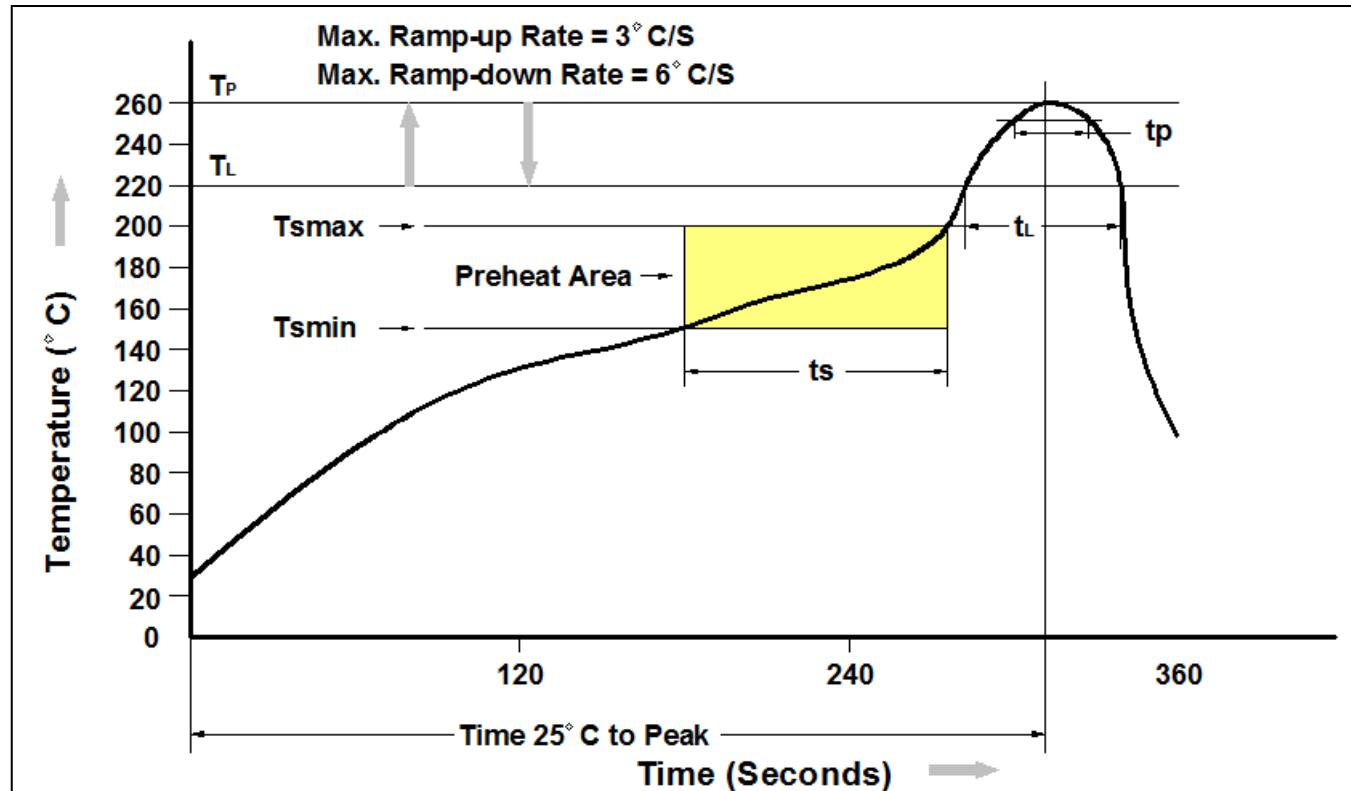
3400 : Device Number

Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CT3400-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T_{smin})	150 °C
Temperature Max. (T_{smax})	200 °C
Time (t_s) from (T_{smin} to T_{smax})	60-120 seconds
Ramp-up Rate (t_L to T_p)	3 °C/second max.
Liquidous Temperature (T_L)	217 °C
Time (t_L) Maintained Above (T_L)	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t_p) within 5°C of 260°C	30 seconds
Ramp-down Rate (T_p to T_L)	6 °C/second max
Time 25°C to Peak Temperature	8 minutes max.



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